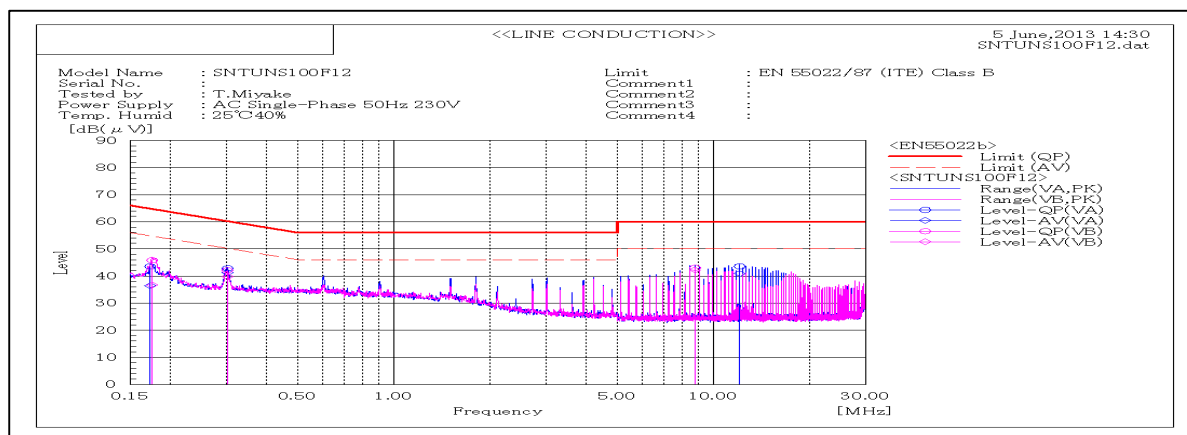
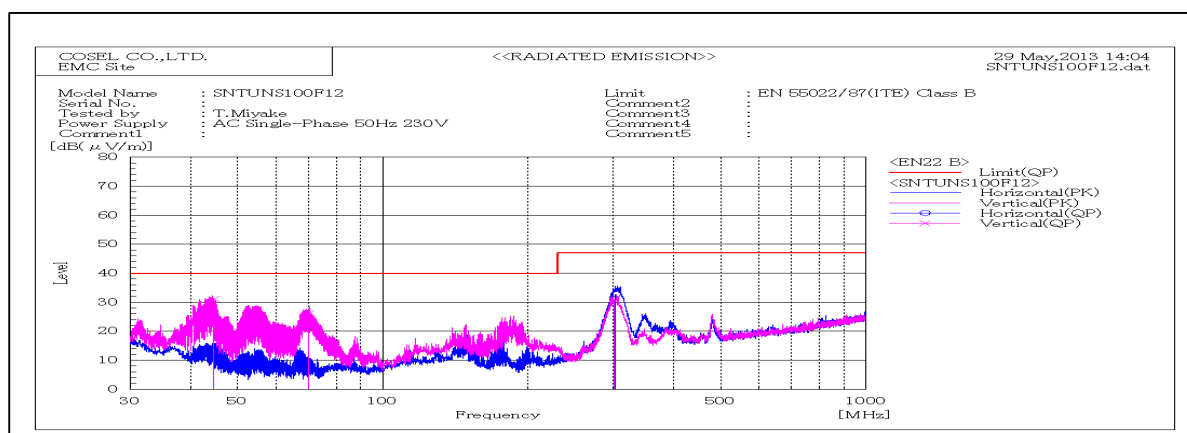


DATA SHEET

Model		SNTUNS100F12	Date	19-Jul-13
Test		EMI Line conduction & Radiated emission	Temp.	25 degreeC
			Humid.	40 %RH
			Tested by	T.Miyake



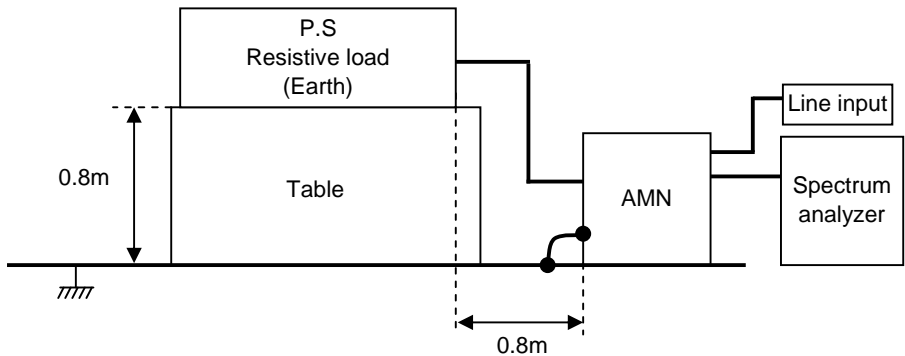
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.17315	VA	23.3	16.3	20.2	43.5	36.5	64.8	54.8	21.3	18.3	Pass	
0.1758	VB	25.6	16.4	20.2	45.8	36.6	64.7	54.7	18.9	18.1	Pass	
0.30144	VB	22	19.7	20.1	42.1	39.8	60.2	50.2	18.1	10.4	Pass	
0.30212	VA	22.7	21.1	20.1	42.8	41.2	60.2	50.2	17.4	9	Pass	
8.74904	VB	22.6	21.8	20.4	43	42.2	60	50	17	7.8	Pass	
12.0692	VA	22.8	20.2	20.7	43.5	40.9	60	50	16.5	9.1	Pass	



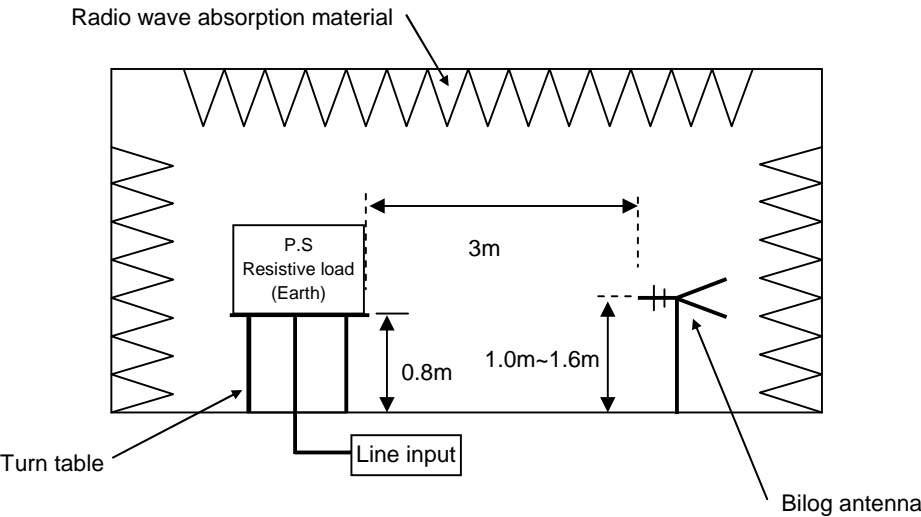
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
44.651	V	Stable	50	-19	31	40	9	Pass	103	213		
70.306	V	Stable	46.8	-20.6	26.2	40	13.8	Pass	124	55		
301.498	V	Stable	46.3	-15.8	30.5	47	16.5	Pass	103	92		
303.178	H	Stable	50.3	-17.6	32.7	47	14.3	Pass	105	123		

DATA SHEET		Date	19-Jul-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission



Test:EMI

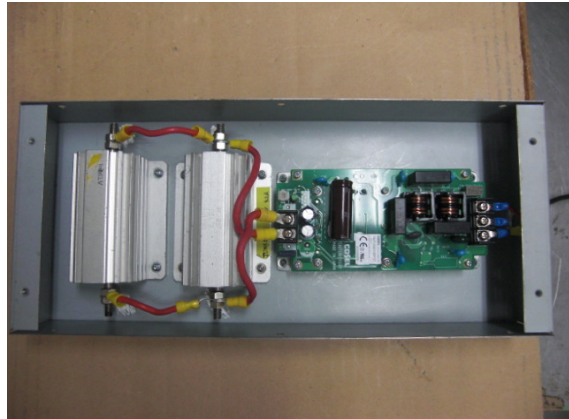
Model Name: SNTUNS100F Series

○ Photographs of Test Set-Up

LINE CONDUCTION



(A) Outside of a case

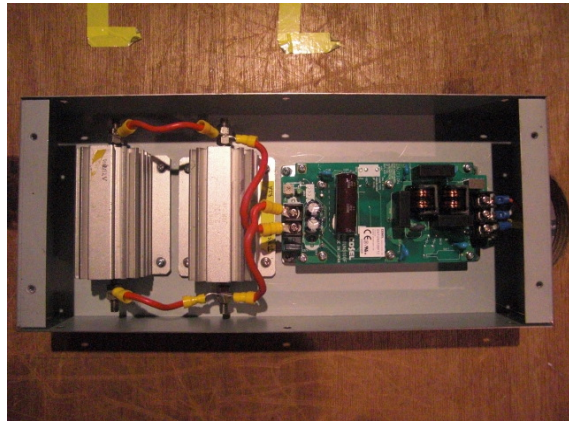


(B) Inside of a case

RADIATED EMISSION



(C) Outside of a case



(D) Inside of a case